Nòtice of References Cited Application/Control No. 10/593,434 Examiner Hai H. Huynh Applicant(s)/Patent Under Reexamination LUDWIG ET AL. Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification	
*	Α	US-6,823,738 B1	11-2004	Wlodarczyk et al.	73/705	
* в		US-7,032,438 B2	04-2006	Heinzelmann et al.	73/115	
*	O	US-2005/0061063 A1	03-2005	Haussner et al.	073/116	
*	D	US-2006/0053875 A1	Haussner et al.	073/116		
*	E	US-2007/0245806 A1	10-2007	Hirose et al.	73/35.13	
	F	US-				
	G	US-				
	Н	US-				
	ı	US-				
	J	US-				
	K	US-				
	L	US-				
	М	US-				

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 2007-78330	03-2007	Japan	Ito et al	F02D-35/00
	0	JP 2006-10306	01-2006	Japan	Omura et al	F02P-19/00
	Р					
	Q				·	
	R					
	s					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)	
	U		
	V		
	w		
	x		

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.